

**Search Notes**

Application/Control No.

10/790,296

Examiner

Paul Dinh

Applicant(s)/Patent under  
Reexamination

PHAN ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	19-21	6/1/2005	PD
382	145	6/1/2005	PD
438	14, 16	6/1/2005	PD
430	5, 22, 30	6/1/2005	PD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST, IEEE	6/1/2005	PD